


<b>Search Notes</b>  	<b>Application/Control No.</b>  10608023	<b>Applicant(s)/Patent Under Reexamination</b>  YANO ET AL.
	<b>Examiner</b>  CHAN S PARK	<b>Art Unit</b>  2625

SEARCHED			
Class	Subclass	Date	Examiner
358	1.15, 1.13	4/10/07	CP
348	207.2	4/10/07	CP

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (see the updated history)	5/20/08	CP
Inventor search	5/20/08	CP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	SAME AS ABOVE		